Search Notes	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/684,466	CHANG, HYUK
	Examiner	Art Unit
	Julian Mercado	1745

SEARCHED			
Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)	DATE	EXMR
EAST keyword search (attached)	12/5/05	
Inventor search EAST		